ABSTRACT OF THE DISCLOSURE

Two temporary buffers are employed alternatively storing a fail address data designated from a test operation, in which one of the temporary buffers transfers the fail address data to a data buffer in order to perform a repair analysis while the other one is storing the fail address data. Accordingly, the test and repair analysis operations are simultaneously performed. The capability of the rearrangement that includes the movement and exchange between the column and row fail address data enhances redundancy efficiency and yields of the memory device.

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